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1. DMEA122-001: High Speed, High Resolution X-ray System for Inspecting Integrated Circuits

   Release Date: 04-24-2012Open Date: 05-24-2012Due Date: 06-27-2012Close Date: 06-27-2012

   OBJECTIVE: Develop an affordable x-ray microscope system for use in performing integrated circuit (IC) reverse engineering. DESCRIPTION: X-ray microscopy using a synchrotron as the x-ray source has been demonstrated to be an extremely valuable tool in the performance of high throughput integrated circuit evaluation and reverse engineering efforts. However, synchrotron x-ray sources are prohi ...

   SBIR Defense Microelectronics Activity

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